



**ALPHA & OMEGA**  
SEMICONDUCTOR



## AO6603

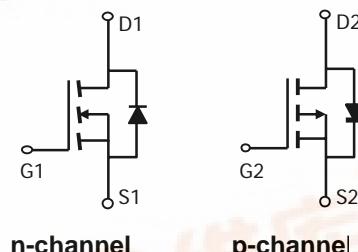
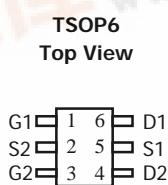
### Complementary Enhancement Mode Field Effect Transistor

#### General Description

The AO6603 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications. Standard Product AO6603 is Pb-free (meets ROHS & Sony 259 specifications). AO6603L is a Green Product ordering option. AO6603 and AO6603L are electrically identical.

#### Features

n-channel	p-channel
$V_{DS}$ (V) = 20V	-30V
$I_D$ = 1.7 ( $V_{GS}$ = 4.5V)	-2.5A
$R_{DS(ON)}$	
< 225mΩ ( $V_{GS}$ = 4.5V)	< 135mΩ ( $V_{GS}$ = -10V)
< 290mΩ ( $V_{GS}$ = 2.5V)	< 185mΩ ( $V_{GS}$ = 2.5V)
< 425mΩ ( $V_{GS}$ = 1.8V)	< 265mΩ ( $V_{GS}$ = 1.8V)



#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	20	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	1.7	-2.3	A
$T_A=70^\circ\text{C}$		1.4	-1.8	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	15	-30	
Power Dissipation	$P_D$	1.15	1.15	W
$T_A=70^\circ\text{C}$		0.73	0.73	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	°C

#### Thermal Characteristics: n-channel and p-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	78	110	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		106	150	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	64	80	°C/W

**N-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			25	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.55	0.8	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	5			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=1.7\text{A}$ $T_J=125^\circ\text{C}$		186 262	225 315	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=1\text{A}$		241	290	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}, I_D=0.7\text{A}$		326	425	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=1.7\text{A}$		2.8		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.69	1	V
$I_S$	Maximum Body-Diode Continuous Current				0.4	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		101	125	pF
$C_{\text{oss}}$	Output Capacitance			17		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			14		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3	4	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=1.7\text{A}$		1.57	8.1	nC
$Q_{\text{gs}}$	Gate Source Charge			0.13		nC
$Q_{\text{gd}}$	Gate Drain Charge			0.36		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=3\Omega, R_{\text{GEN}}=3\Omega$		3.2		ns
$t_r$	Turn-On Rise Time			4		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			15.5		ns
$t_f$	Turn-Off Fall Time			2.4		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$		6.7	16	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$		1.6		nC

A: The value of  $R_{\text{0JA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $\leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{0JA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{0JL}}$  and lead to ambient.

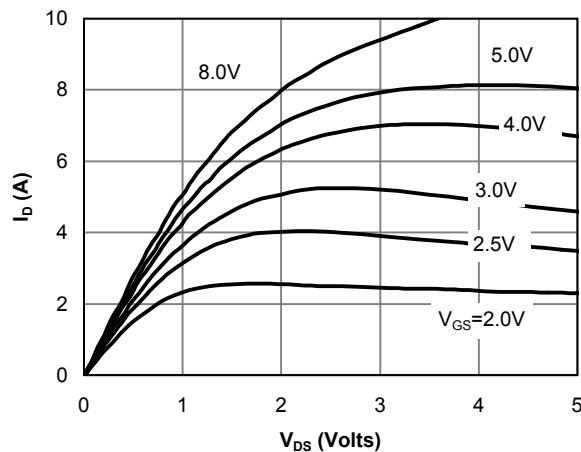
D. The static characteristics in Figures 1 to 6 are obtained using 80μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

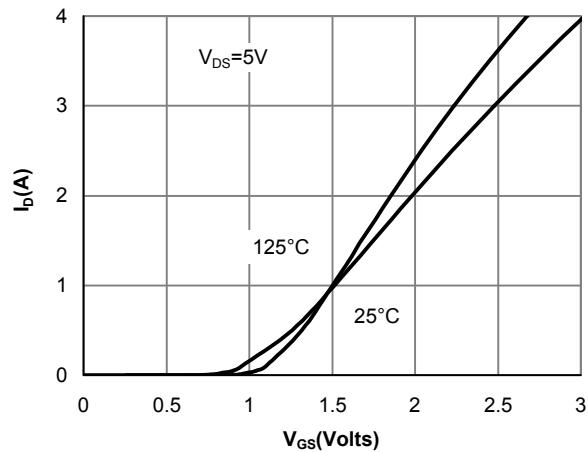
Rev 2: Sept 2005

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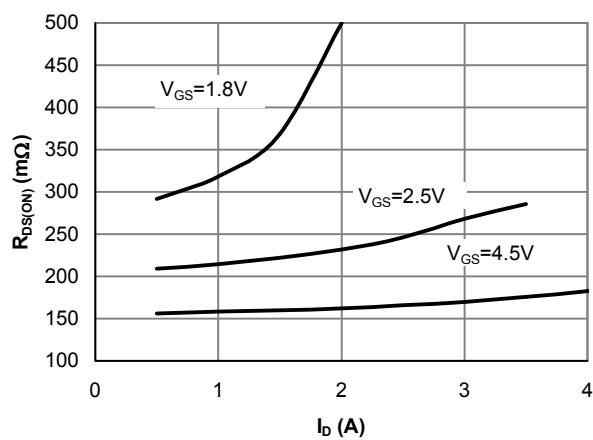
## N-CHANNEL TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



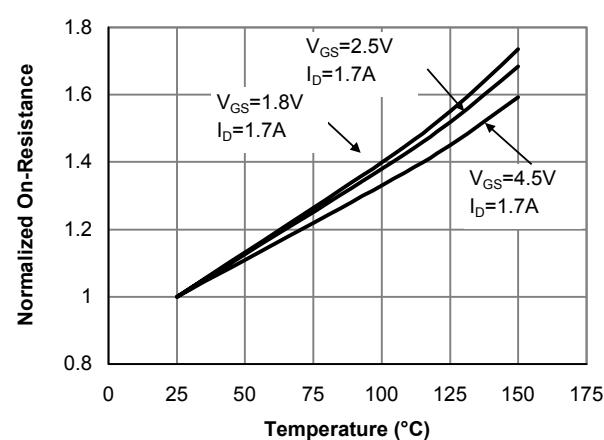
**Fig 1: On-Region Characteristics**



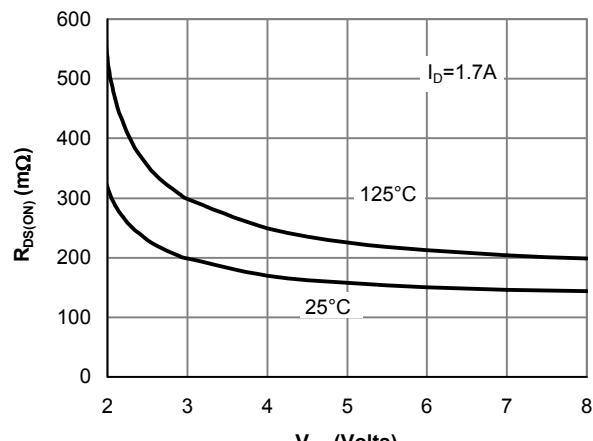
**Figure 2: Transfer Characteristics**



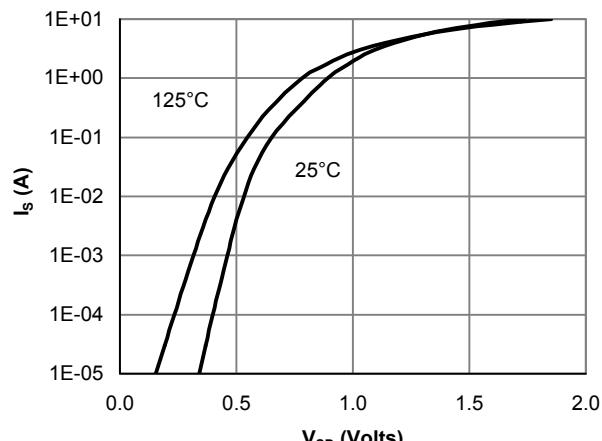
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body-Diode Characteristics**

## N-CHANNEL TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

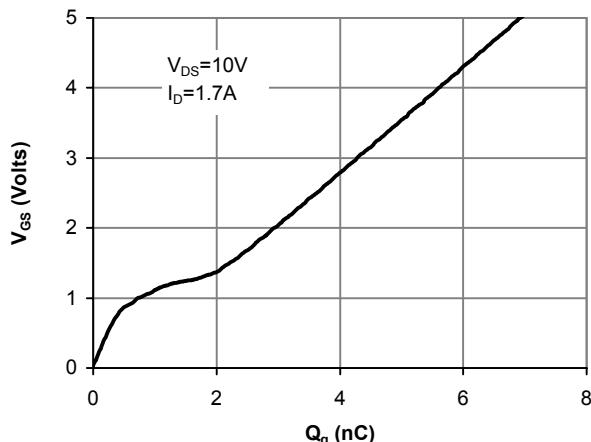


Figure 7: Gate-Charge Characteristics

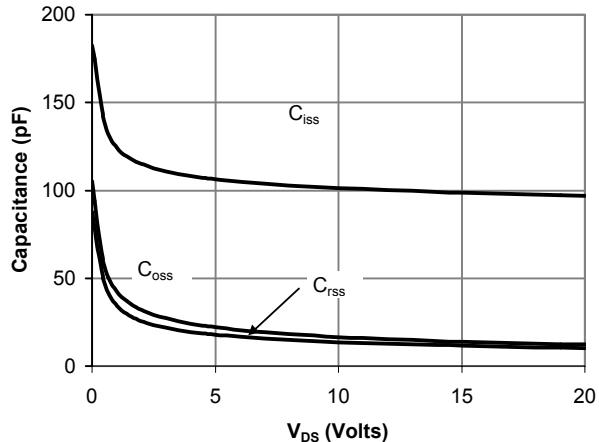


Figure 8: Capacitance Characteristics

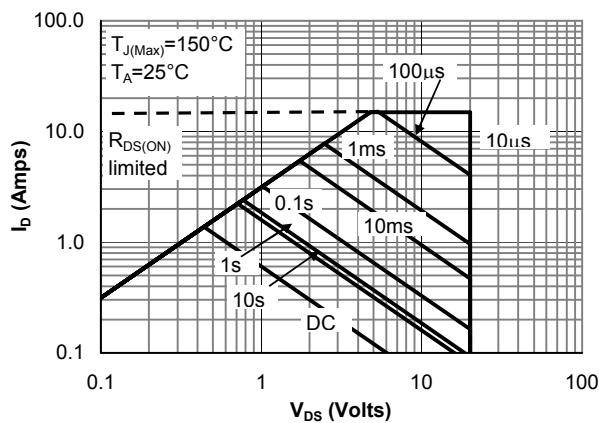


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

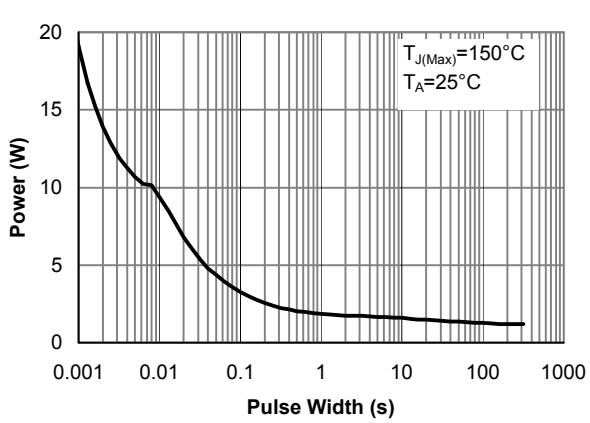


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

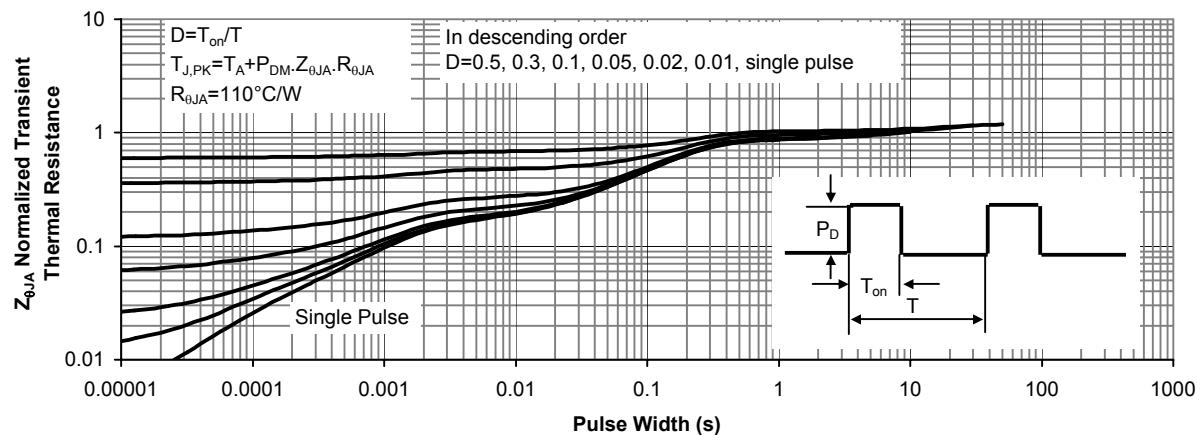


Figure 11: Normalized Maximum Transient Thermal Impedance

**P-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$			-1	$\mu\text{A}$
				$T_J=55^\circ\text{C}$	-5	
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.6	-1	-1.4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-10			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-2.3\text{A}$		107	135	$\text{m}\Omega$
			$T_J=125^\circ\text{C}$			
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		135	185	
		$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$		195	265	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-2.3\text{A}$		8		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.85	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-1.35	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		409		pF
$C_{\text{oss}}$	Output Capacitance			55		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			42		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		12		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-15\text{V}, I_D=-2.5\text{A}$		0.72		nC
$Q_{\text{gs}}$	Gate Source Charge			1.34		nC
$Q_{\text{gd}}$	Gate Drain Charge			4.8		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=6\Omega, R_{\text{GEN}}=6\Omega$		8.5		ns
$t_r$	Turn-On Rise Time			10		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			55		ns
$t_f$	Turn-Off Fall Time			25.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-2.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		26		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-2.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		15.6		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D: The static characteristics in Figures 1 to 6,12,14 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## P-CHANNEL: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

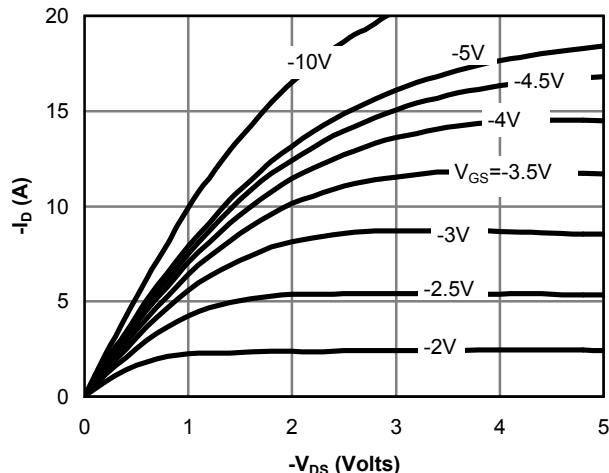


Fig 1: On-Region Characteristics

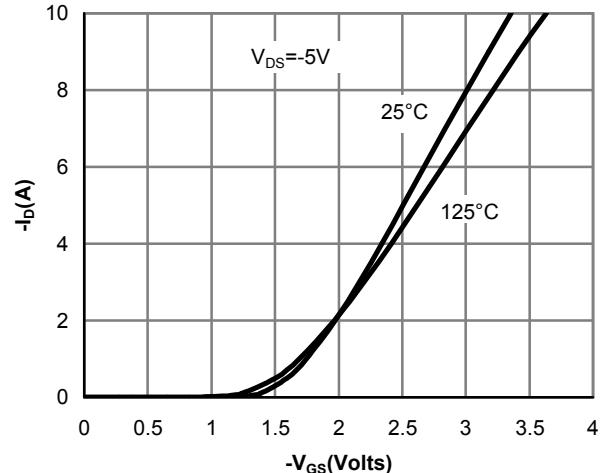


Figure 2: Transfer Characteristics

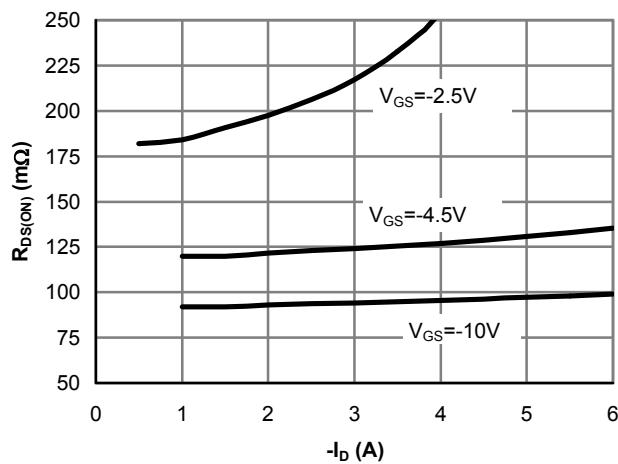


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

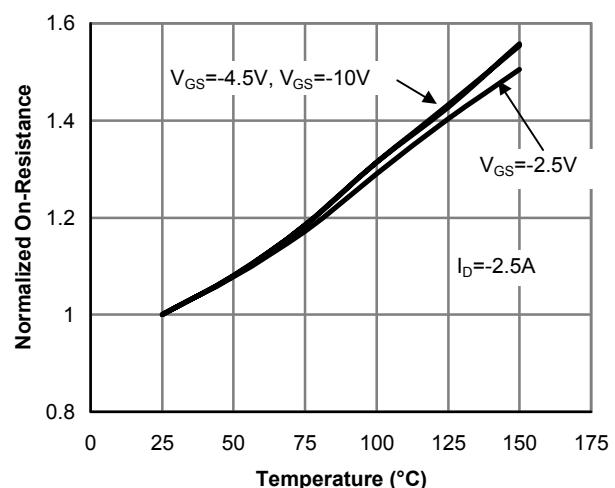


Figure 4: On-Resistance vs. Junction Temperature

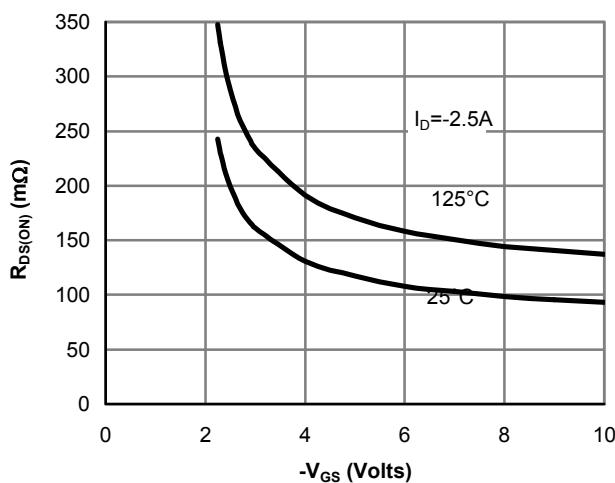


Figure 5: On-Resistance vs. Gate-Source Voltage

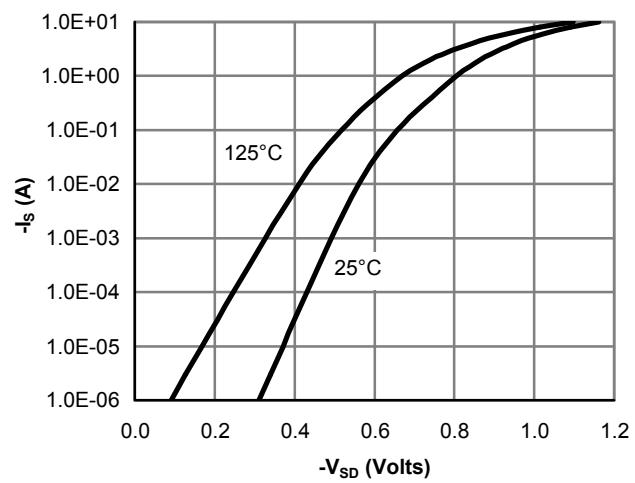


Figure 6: Body-Diode Characteristics

## P-CHANNEL: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

